IBIC2024 - 13th International Beam Instrumentation Conference



Contribution ID: 47 Contribution code: WEP02

Type: Poster Presentation

Bunch-by-bunch profile measurement during beam available time

Wednesday, 11 September 2024 14:20 (1h 30m)

One bunch-by-bunch Profile Measurement System has been built in the Hefei Light Source HLS-II to measure the profile positions and profile sizes of each bunch in the storage ring during beam available time. Corresponding configuration of the system and the analysis of the measurement error are described in detail in this paper.

Footnotes

Funding Agency

I have read and accept the Privacy Policy Statement

Yes

Primary authors: Prof. SUN, Bao-gen (University of Science and Technology of China); WANG, Jigang (University of Science and Technology of China); TANG, Leilei (University of Science and Technology of China); MA, Xiaochao (Budker Institute of Nuclear Physics)

Co-author: WU, Ruizhe (University of Science and Technology of China)

Presenter: WU, Ruizhe (University of Science and Technology of China)

Session Classification: WEP: Wednesday Poster Session

Track Classification: MC4: Transverse Profile and Emittance Monitors